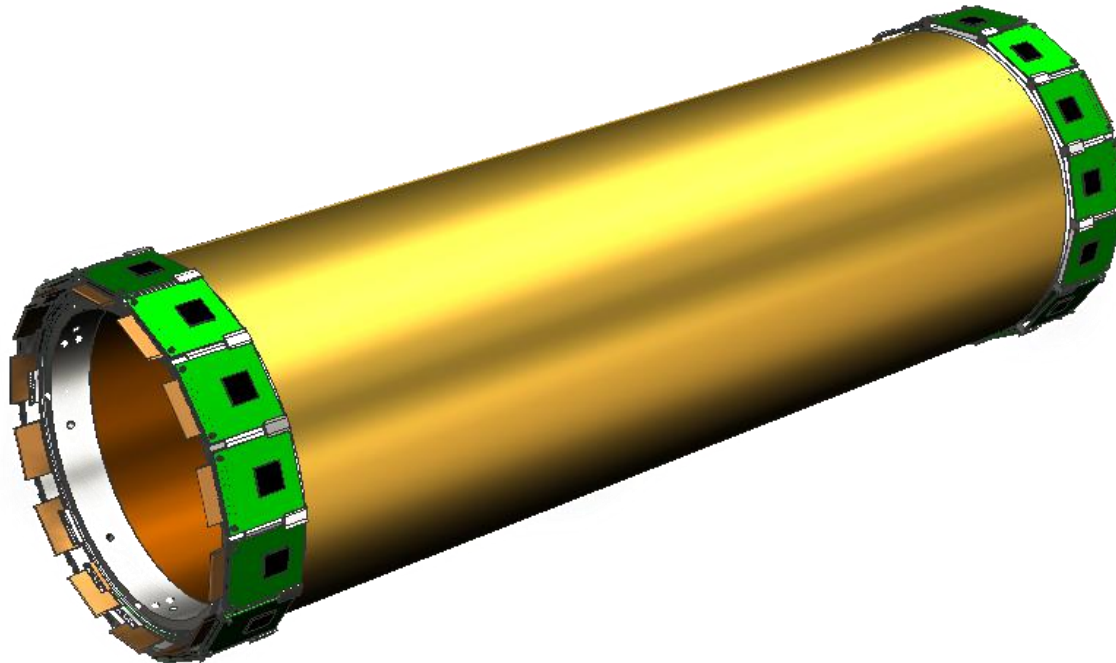


BESIII



## Full triple-GEM digitization in magnetic field

Riccardo Farinelli & Lia Lavezzi & Liangliang Wang



# Outline

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- Simulation technique
- Primary ionization
- Transparency & Avalanche
- Drift properties
- Signal clusterization



# Simulation technique - I

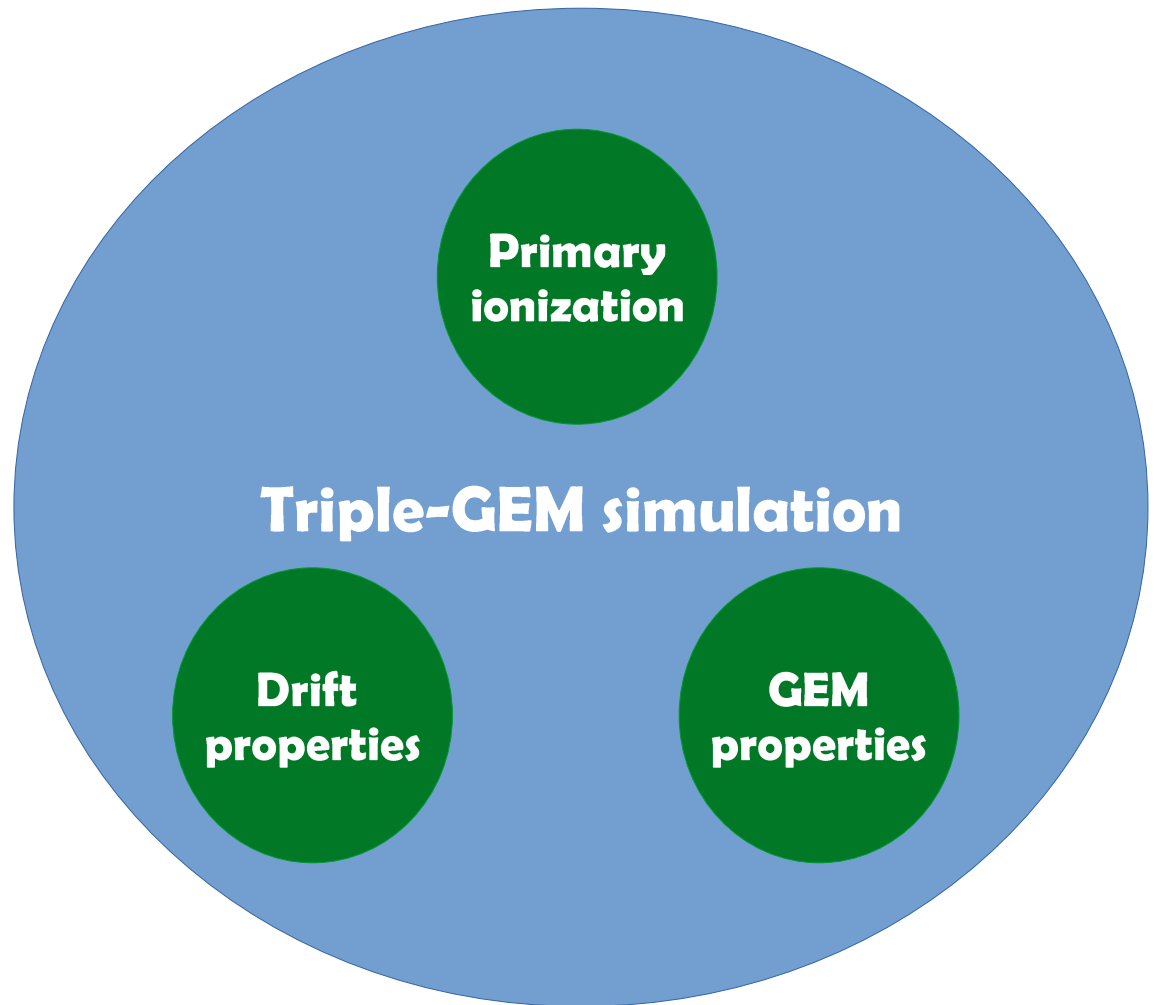
---

GARFIELD is too time demanding to simulate the full triple-GEM signal formation due to a ionizing particle → divide the simulation into 3 parts:

**1** Ionization

**2** Gain

**3** Diffusion



---

The 3 topics are independent, then we can study them separately

# Primary ionization - I

**GOAL** – parametrize the **number & position** of primary/secondary electrons produced in the drift gas

- The ionizing particle interacts with the gas and create primary electrons
- If their energy is sufficient, each primary electron can create secondary electrons:
  - we assume that the position of the secondary electrons is the same of the primary one
  - We call this agglomerate of electrons “*electron cluster*”



# Primary ionization - II

---

**We need [from GARFIELD]**

- # of electrons generated in the Drift gap
- Their generation position

**They depend on:**

- gas mixture
- particle momentum
- particle path



# Primary ionization - II

---

**We need [from GARFIELD]**

- # of electrons generated in the Drift gap
- Their generation position

**They depend on:**

- gas mixture —————→
- particle momentum —————→
- particle path —————→

**We use:**

- Argon: $i\text{C}_4\text{H}_{10}$
- 1 GeV/c
- (For now) only orthogonal tracks



# Primary ionization - II

We need [from GARFIELD]

- # of electrons generated in the drift gap
- Their generation position

They depend on:

- gas mixture —————→
- particle momentum —————→
- particle path —————→

We use:

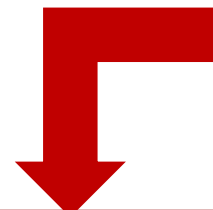
- Argon:iC<sub>4</sub>H<sub>10</sub>

- 1 GeV/c

- (For n<sub>0</sub> = 10<sup>10</sup> cm<sup>-3</sup> hexagonal

Same dE/dx

Always 5 mm of drift gap



Same distribution of energy loss / simulated track

# Note on the primary ionization

---

For now, the  $dE/dx$  of the track **is simulated**

- $ELOSS = \# \text{ total}^{[*]} \text{ electrons} \times \text{mean energy needed to create an electron-ion pair}$

$^{[*]}$  primary + secondary

In the final version of the digitization, the energy loss will be **input from GEANT4...**

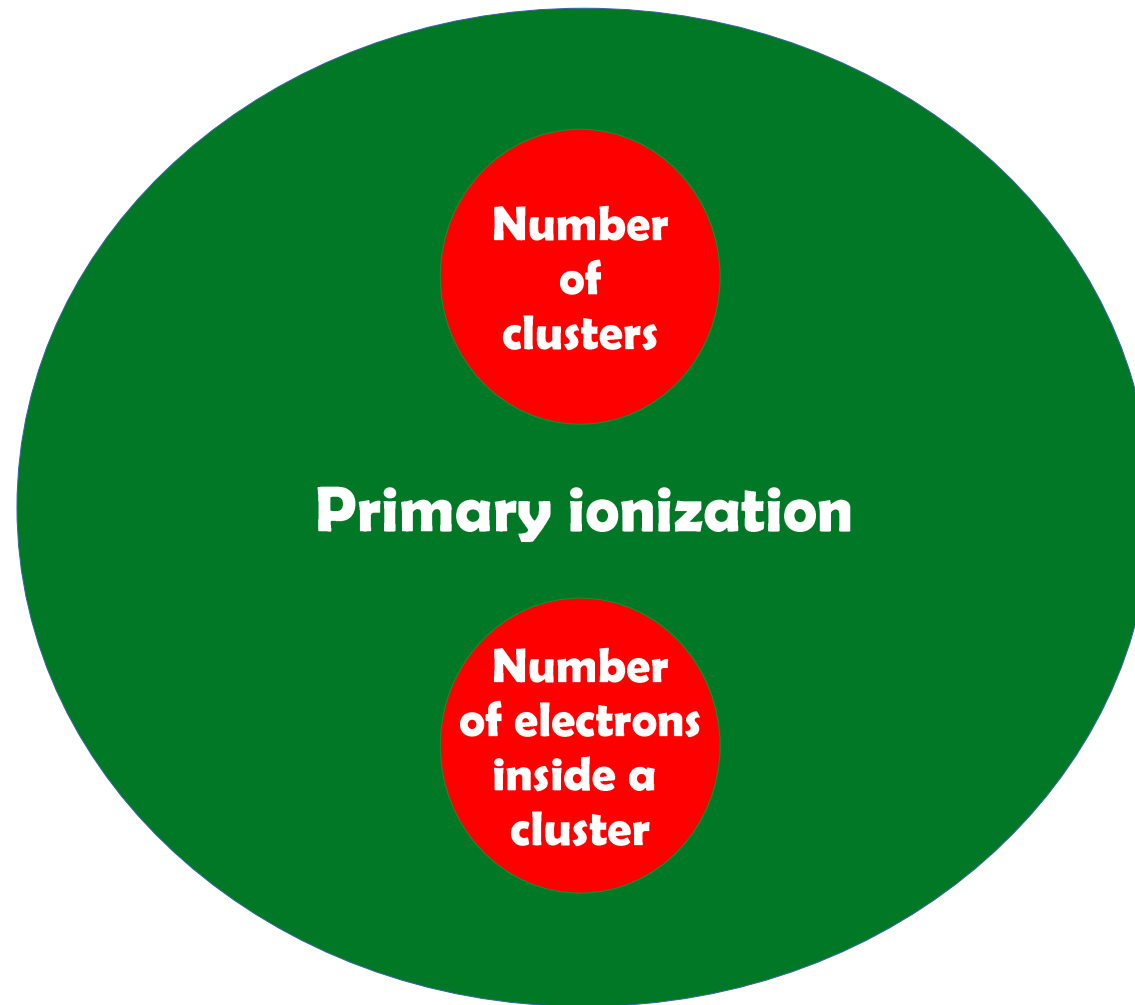
...we will take care of this later





# Primary ionization - III

---



The 2 topics are independent, then we can study them separately

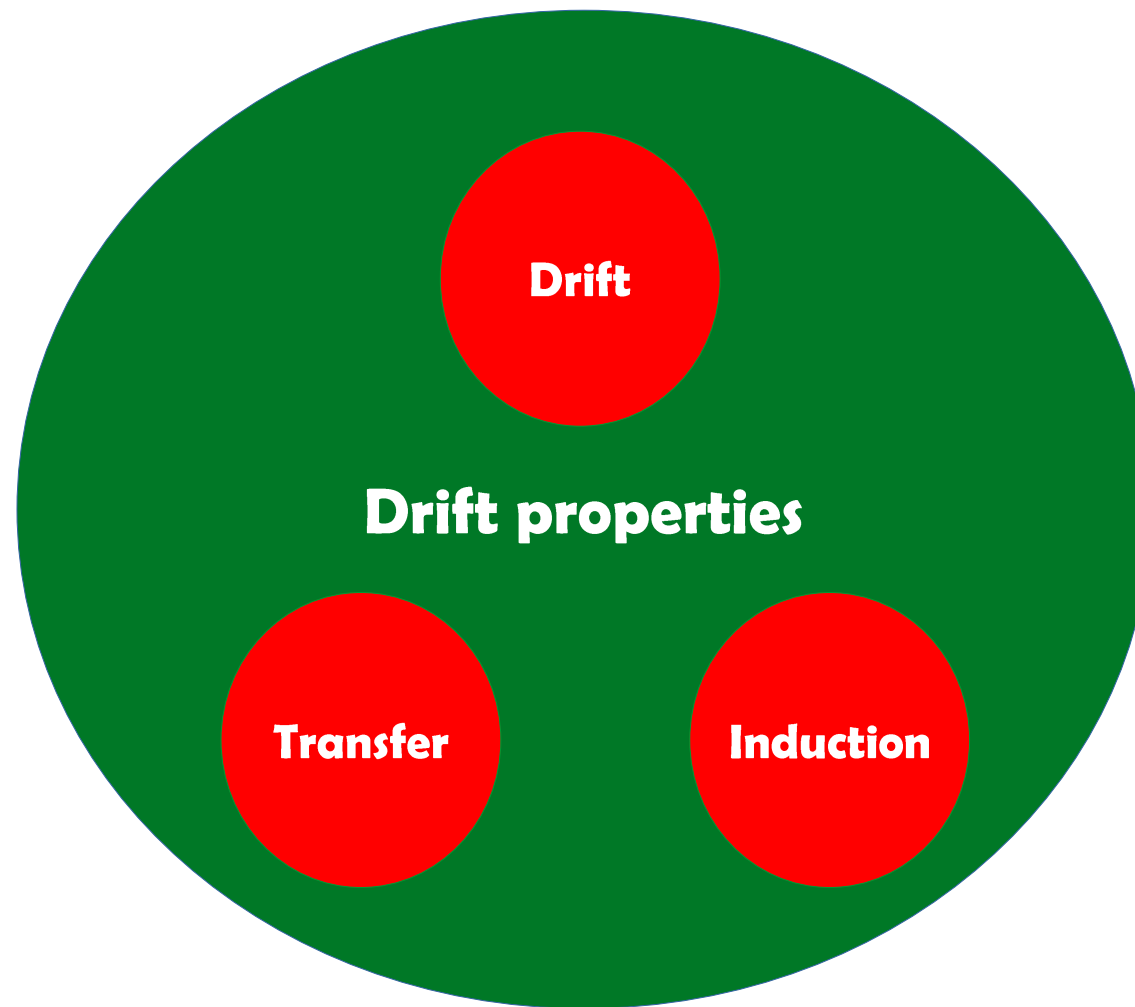


- Given an electron generated in the Drift gap, we have to know its final position and time on the anode
- We have three types of gas region:
  - Drift
  - Transfer
  - Induction



# Drift properties - II

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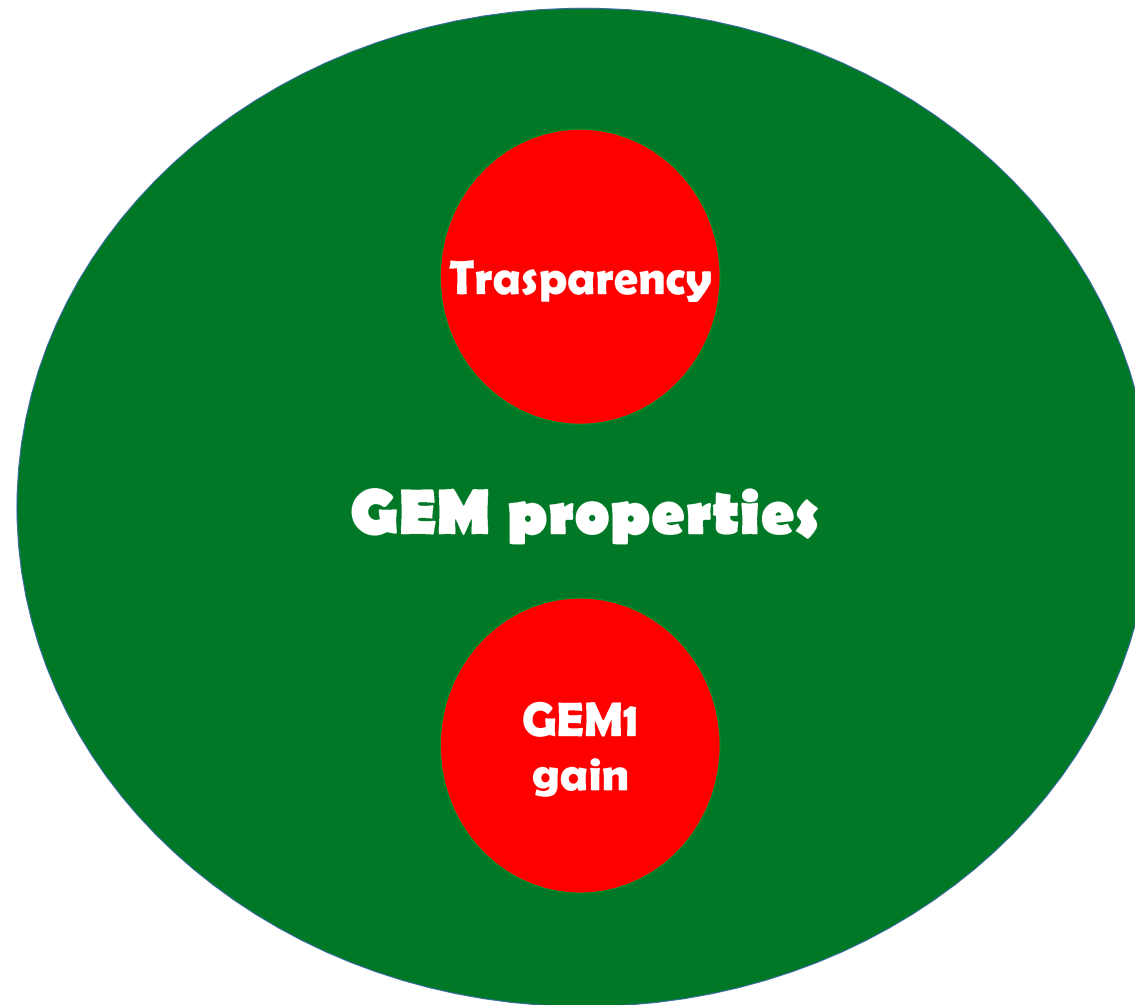


The 3 topics are independent, then we can study them separately



- Each electron crossing a GEM plane generates an avalanche, if it does not fall on the electrodes
- The gain depends on the applied HV: in this simulation we use  $HV = 270V/GEM$
- The capability of an electron to pass on the other side of the GEM plane depends on the applied fields in Transfer and Induction gaps
- The gain of each GEM shows a Landau distribution
- Only the first GEM gain fluctuation influences the distribution at anode. We can consider a mean value for the gain in GEM2 and GEM3





The 2 topics are indipendent, then we can study them separately



# Digitization ingredients

---

1. # generated electron clusters
2. # electrons inside a cluster
3. Spatial shift in the Drift gap
4. Spatial shift in the Transfer gap
5. Spatial shift in the Induction gap
6. GEM1 transparency
7. GEM1 gain





# Digitization ingredients

1. # generated electron clusters
2. # electrons inside a cluster
3. Spatial shift in the Drift gap
4. Spatial shift in the Transfer gap
5. Spatial shift in the Induction gap
6. GEM1 transparency
7. GEM1 gain

## From GARFIELD

10k orthogonal  
 $\mu$  tracks

e- drift in the DG  
e- drift in the TG  
e- drift in the IG

e- avalanche in a GEM



# Digitization recipe

- a) *Generate* the electron clusters
- b) *Generate* the # electrons inside the cluster
- c) *Simulate* the gain
- d) *Obtain* the final position of each electron taking into account the smearing and displacement





# Preparation to step a)

*Generate the electron clusters*

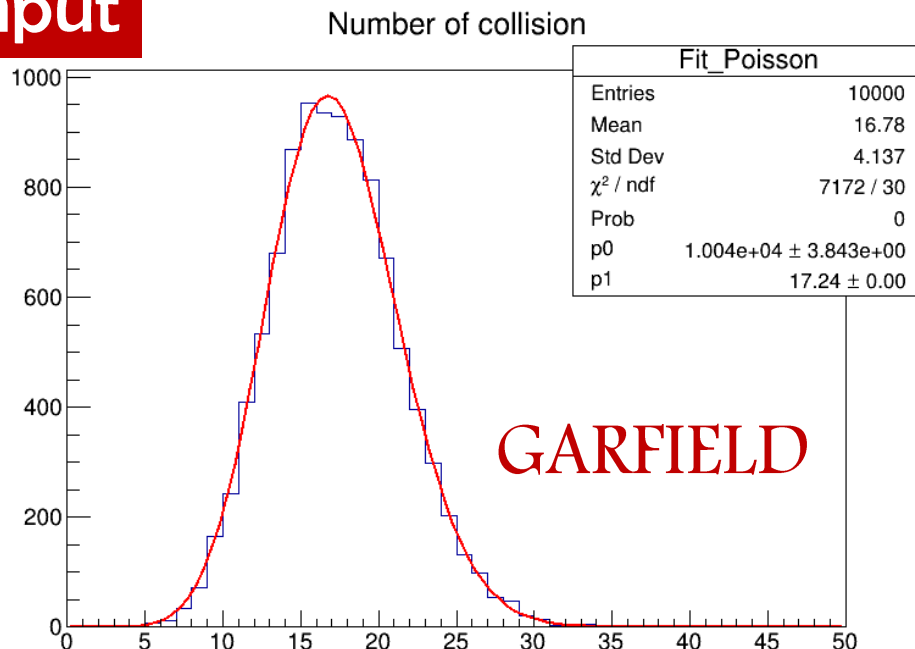
The generation of the electron clusters is a Poisson process

→ sample from an **exponential probability**:

$$p(dz) = A * N * \exp(-N * dz)$$

where  $N$  = mean # clusters in 5mm of Ar:iC<sub>4</sub>H<sub>10</sub>

**input**

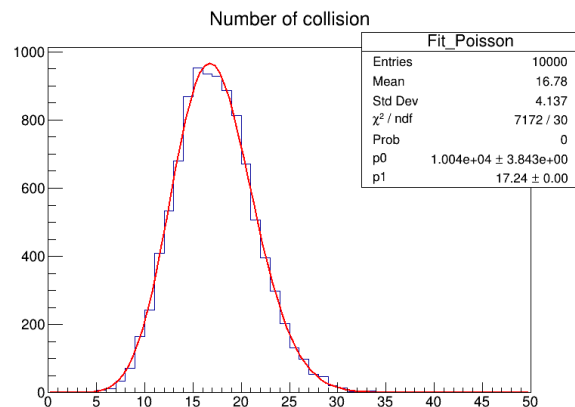


An exponential probability gives the  $dz$  between two consecutive clusters. The  $z$  position is incremented after each cluster and when  $> 5\text{mm}$  the loop stops

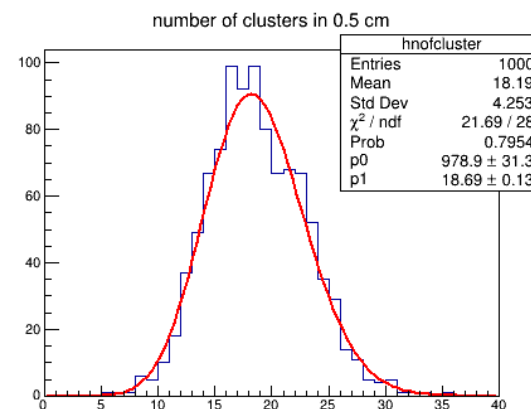


# Check of the step a)

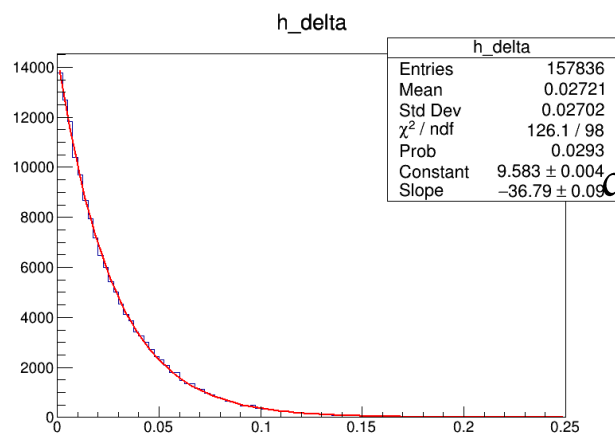
## GARFIELD



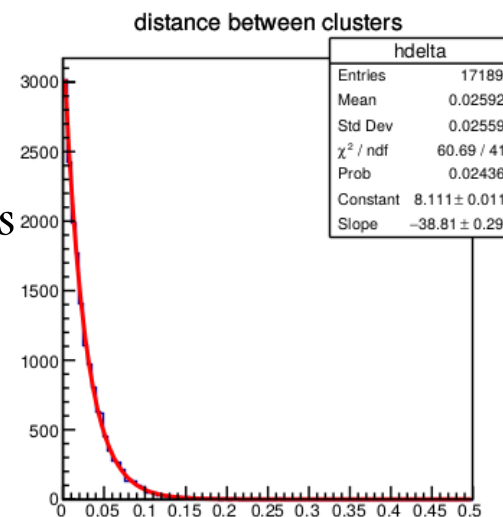
## OUR SIMULATION



Number of clusters

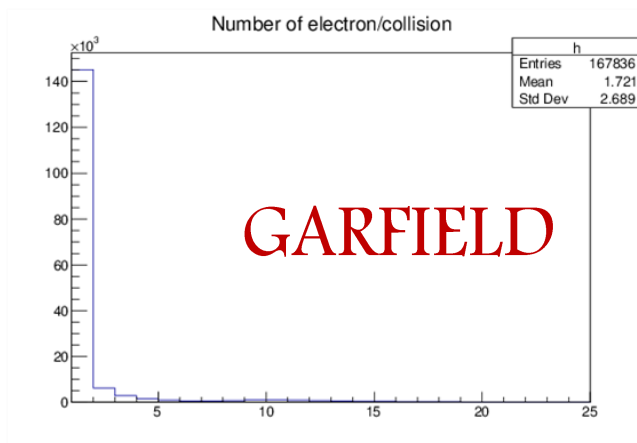


dz between consecutive clusters

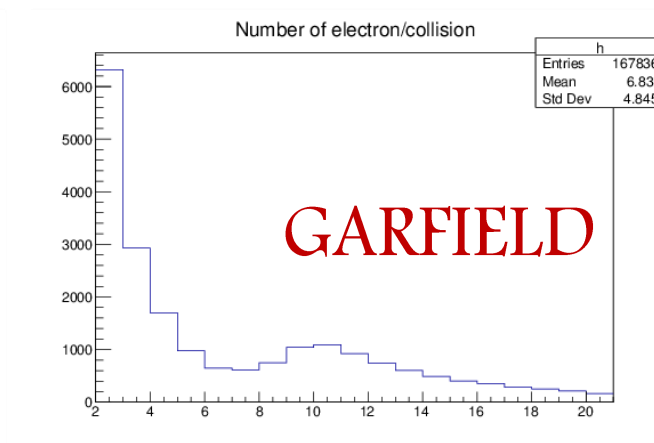


# Preparation to step b)

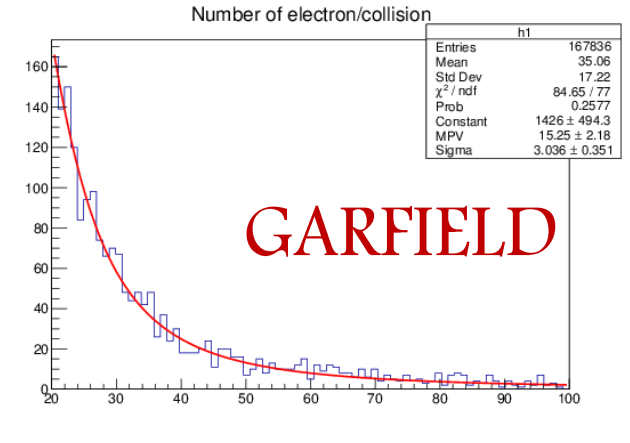
*Generate the number of electrons inside the cluster*



Range 1~25



Range 2~20



Range 20~100

→ We have recorded the probability in [1, 100]

## input

We use:

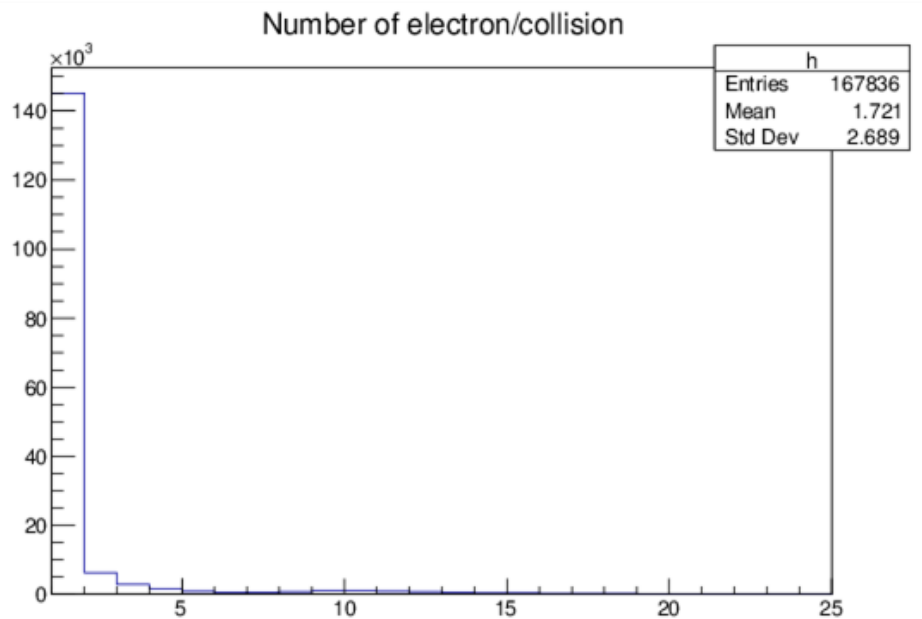
- the simulation discrete value between in [1, 20]
- the sampled value from the Landau fit in [21, 100]

**Approximation:** # electron limit set to 100.

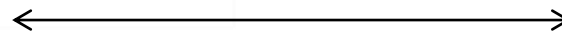
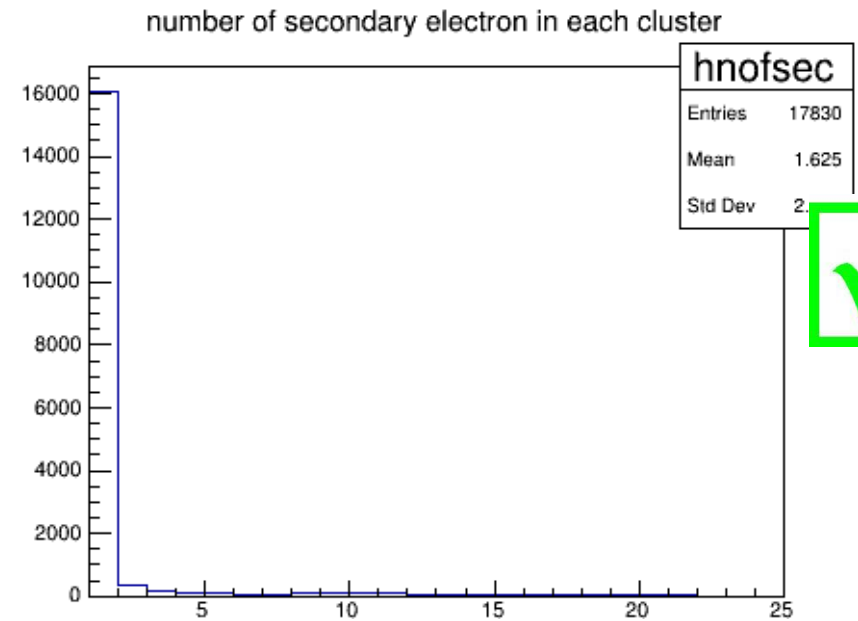


# Check of the step b)

## GARFIELD



## OUR SIMULATION



Number of electrons  
inside a cluster



# Preparation to step c)

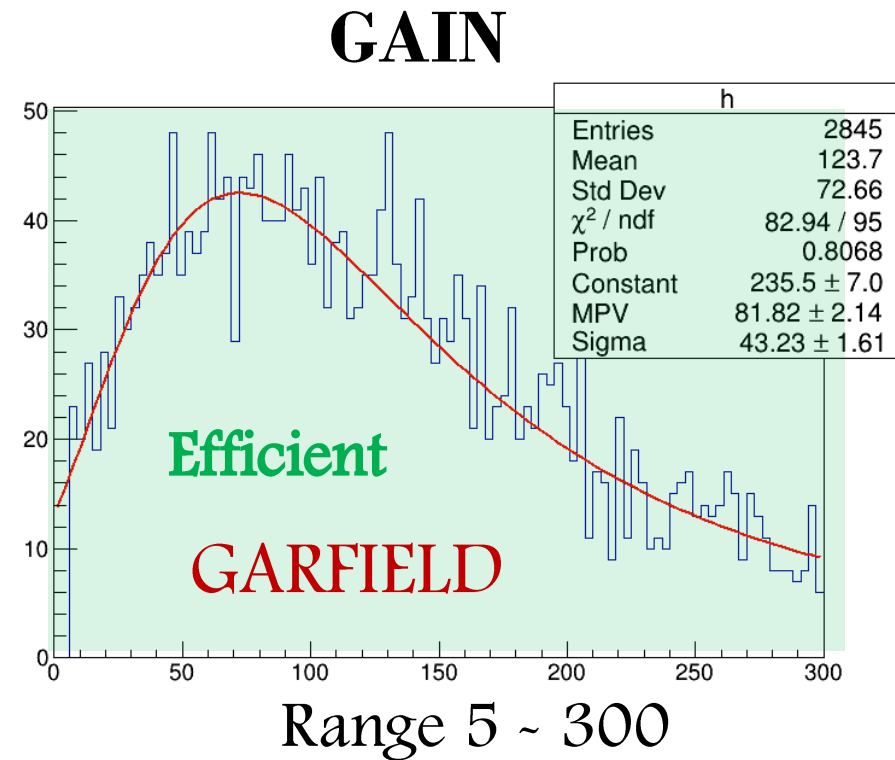
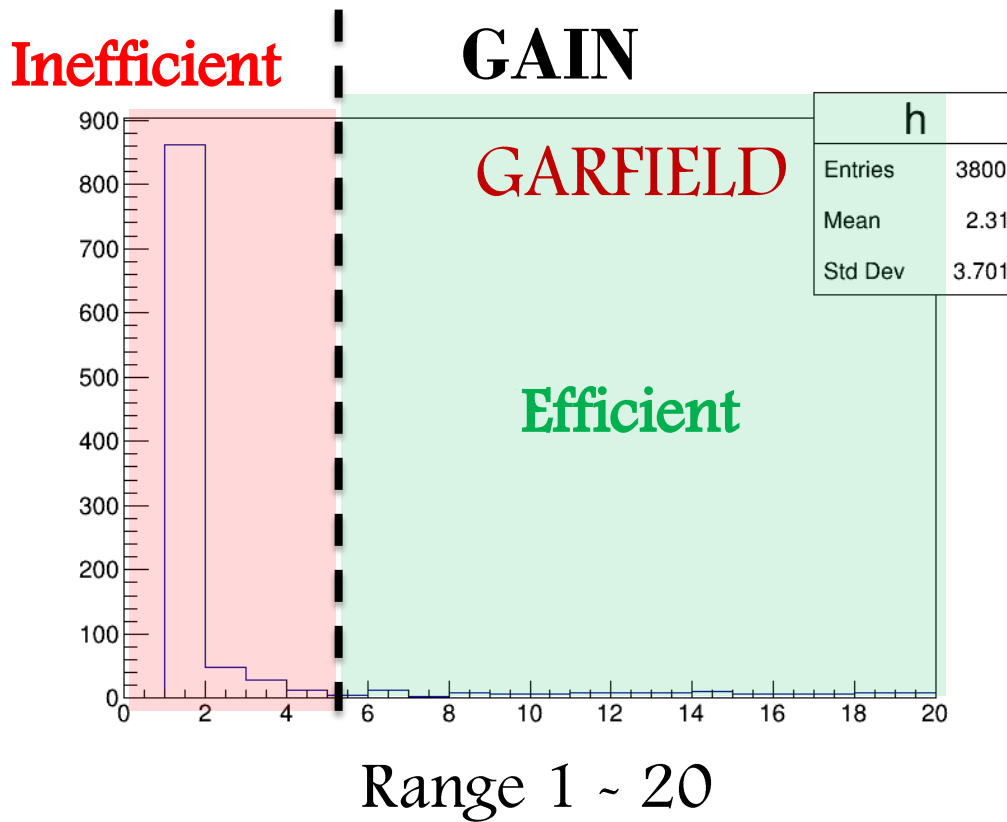
*Simulate the gain*

---

- To evaluate the **gain** and the **transparency** we simulate an electron avalanche from 150  $\mu\text{m}$  *before* GEM1 to 150  $\mu\text{m}$  *after* GEM1
- The number of generated electrons has two behaviors:
  - a peak at the values 0, 1, 2, 3, 4, 5
  - For gains  $> 5 \rightarrow$  Landau shape
- We consider the electron *inefficient* if the gain is below 5  $\rightarrow$   
transparency = #efficient electrons / #total electrons



# Preparation to step c)



**input** Measured transparency = 74.5 %



# Step c)

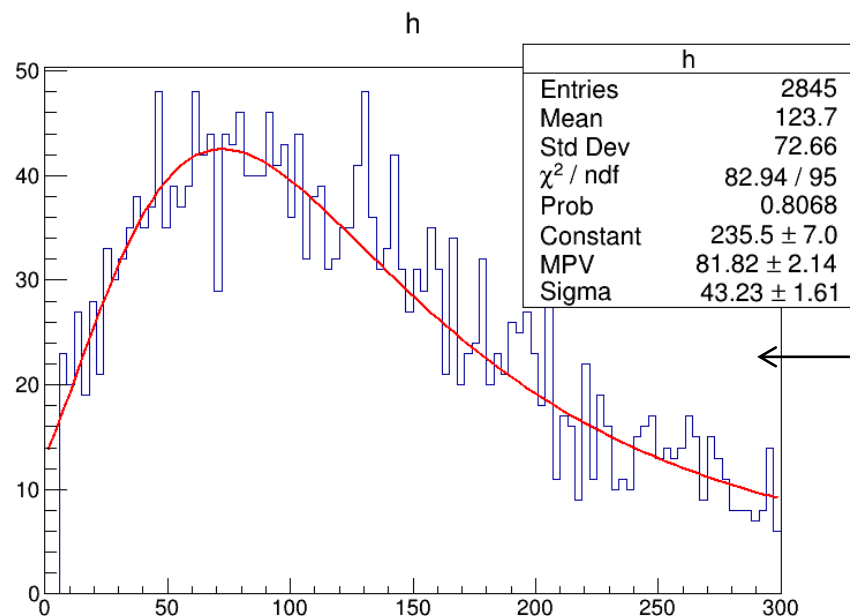
---

- The electrons that survive to the GEM1 (given by the transparency) are amplified
- The gain of the GEM1 is sampled from a Landau
- For GEM2 and GEM3 the gain is set **constant** because the fluctuations there are not important
- We currently use a low gain value in GEM2 and GEM3 otherwise it takes too much time



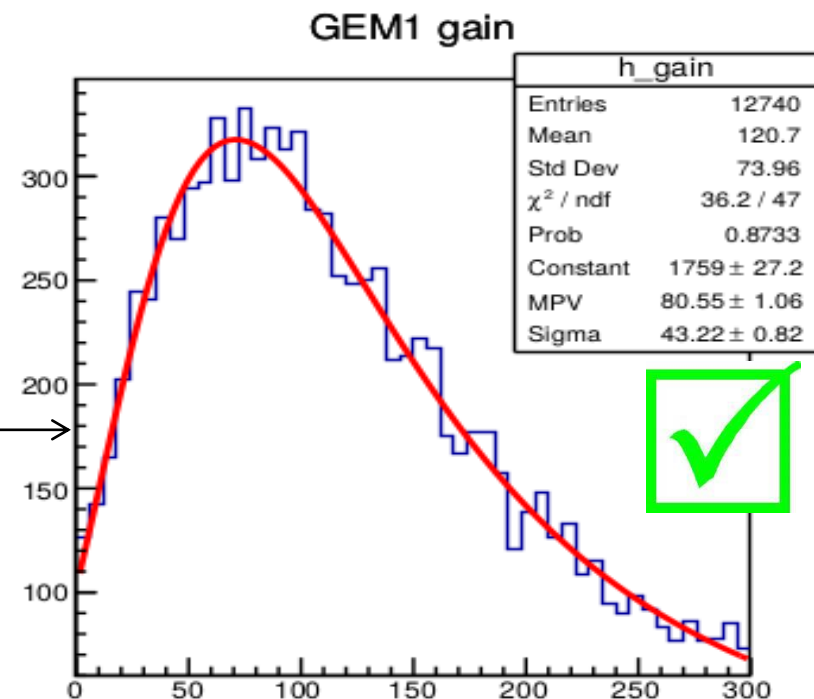
# Check of the step c)

## GARFIELD



## OUR SIMULATION

GEM1 gain





# Preparation to step d)

## *Get the final position of each electron*

---

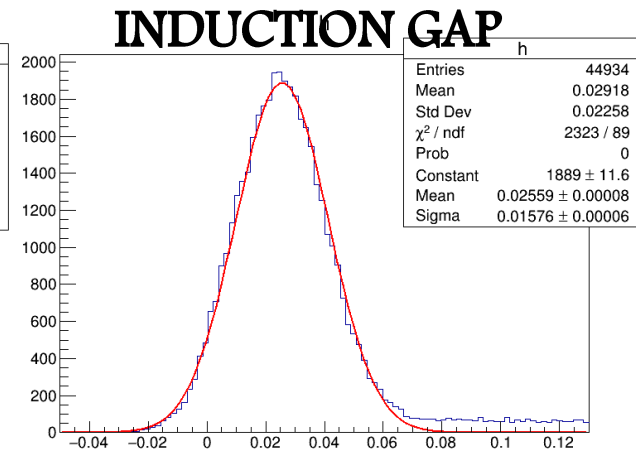
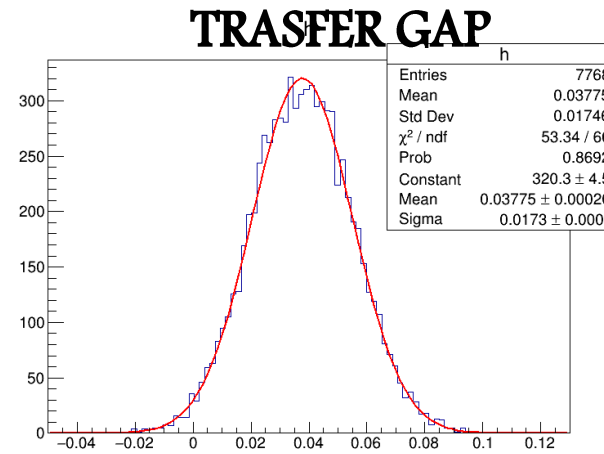
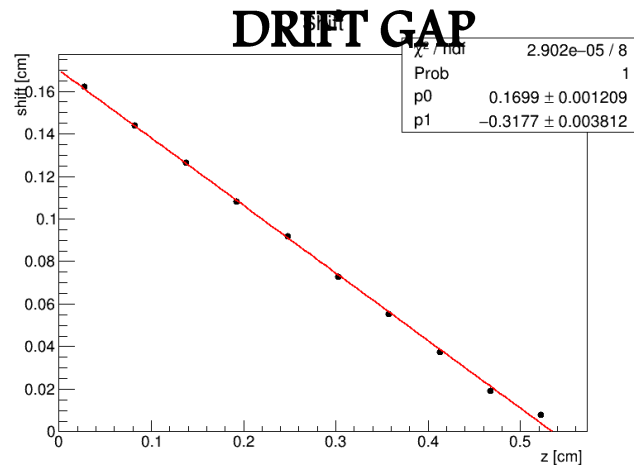
To obtain the complete transport from the Drift gap to the anode we simulate the entire triple-GEM (no empty steps) in separate stages.

The shift depends:

- [in the Drift gap] on the  $z$  of the electron cluster generation. Its drift is simulated to  $150\text{ }\mu\text{m}$  after GEM1 to consider the displacement due to the passage through the GEM hole
- [in the Transfer gap] NOT on  $z$  of the cluster. The electrons drift from  $150\text{ }\mu\text{m}$  after GEM1 to  $150\text{ }\mu\text{m}$  after GEM2 to consider the displacement due to the passage in the GEM hole
- [in the Induction gap]  $\rightarrow$  same as TG

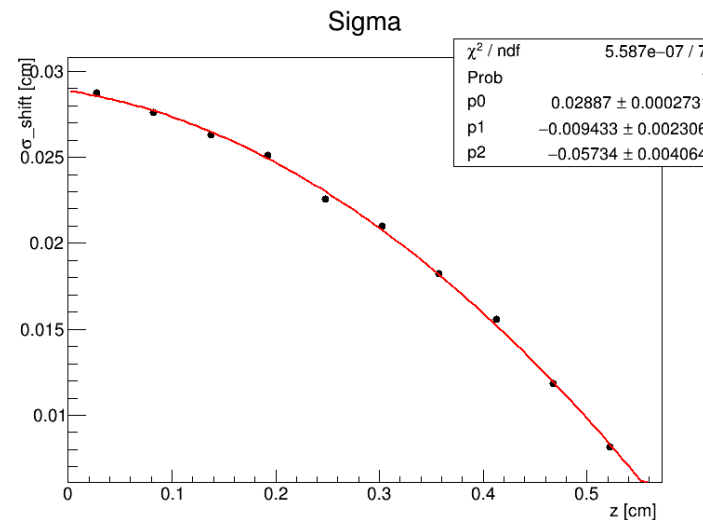


# Preparation to step d)



**input**

$$\mu_{\text{shift\_tot}}(z) = \text{shift\_DG}(z) + 2 * \text{shift\_TG} + \text{shift\_IG}$$



**input**

$$\sigma_{\text{shift}}(z) = \sqrt{[\sigma_{x\_DG}(z)^2 + 2 * \sigma_{x\_TG}(z)^2 + \sigma_{x\_IG}(z)^2]}$$



# Step d)

---

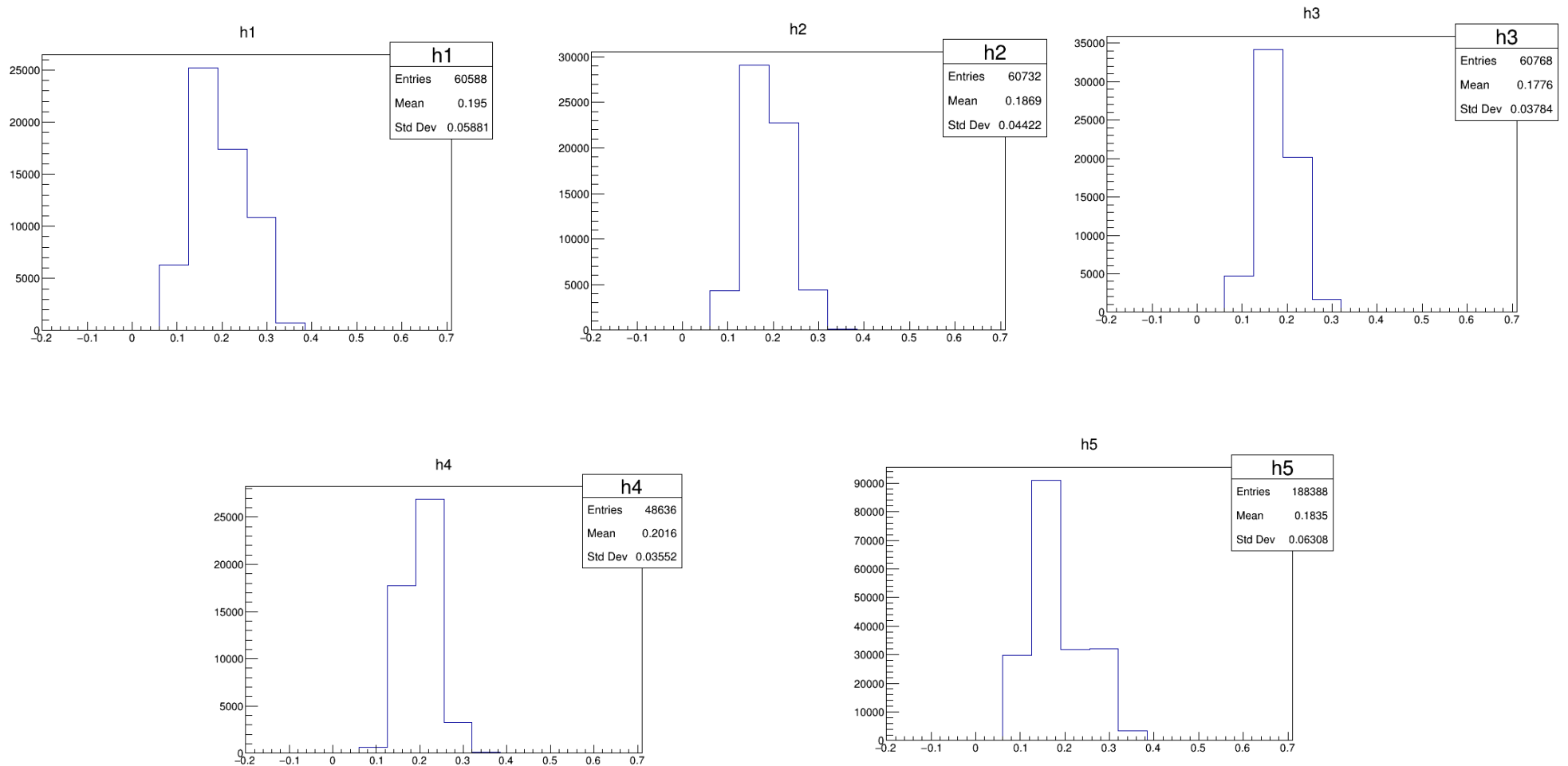
Generate a random Gauss number around  $\mu\_shift(z)$  and smear it by  $\sigma\_shift(z)$  for **each** electron



now cook everything together  
at  $180^{\circ}\text{C}$  for 30 minutes using  
1k simulations ...



# charge distribution @ anode



# Next to do

---

- Simulation of the signal formation on the anode
  - Maxwell?
  - APV simulation on 1° step
  - Interact with the TIGER group for eventual electronics
- $\mu$ TPC reconstruction
- Noise (info from testbeams)
- Charge threshold
- Test on tracks @ different angles
- Tune the simulation with testbeam results
- Use  $dE/dx$  from Geant4 as input



# Next to do

---

- Simulation of the signal formation on the anode (!)
  - Maxwell?
  - APV simulation on 1° step
  - Interact with the TIGER group for eventual electronics
- $\mu$ TPC reconstruction (!)
- Noise (info from testbeams)
- Charge threshold
- Test on tracks @ different angles
- Tune the simulation with testbeam results (!)
- Use dE/dx from Geant4 as input
- Anything else?

**IMPORTANT – deadline may 2017**



# spare

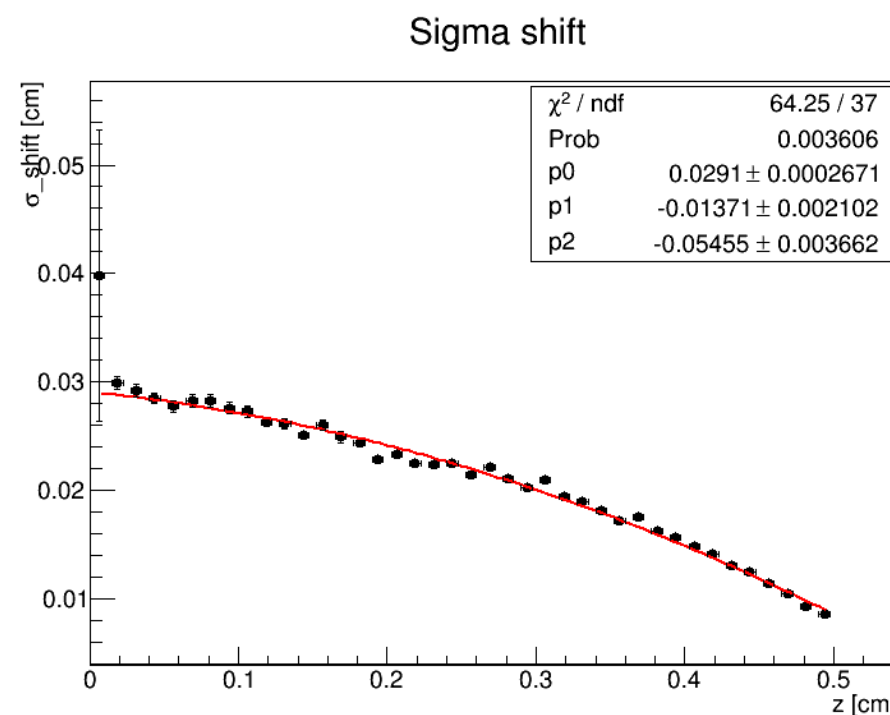
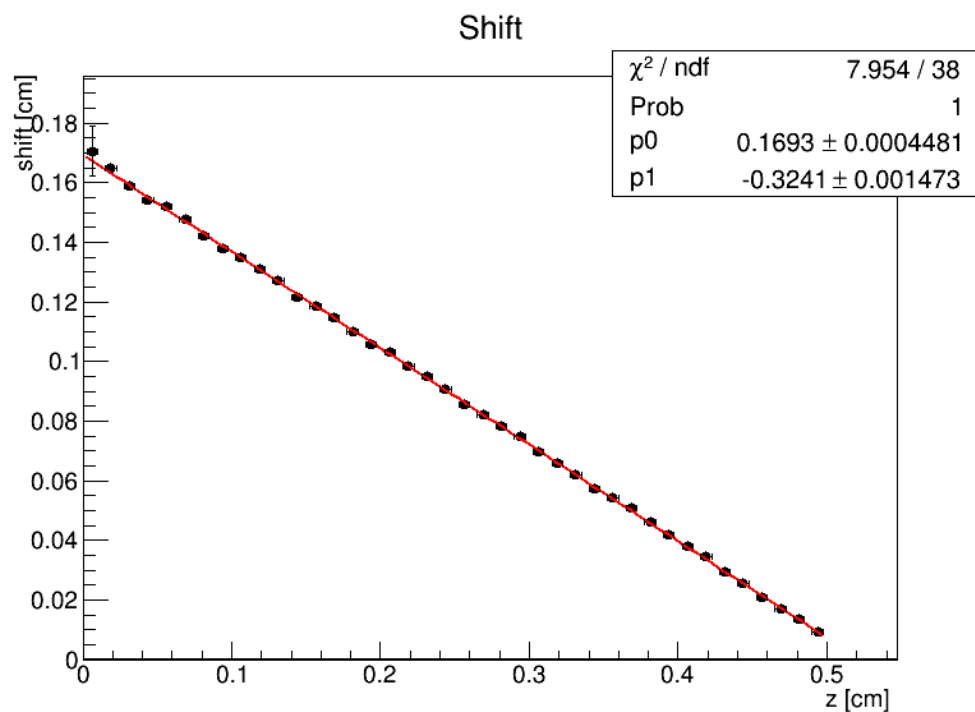
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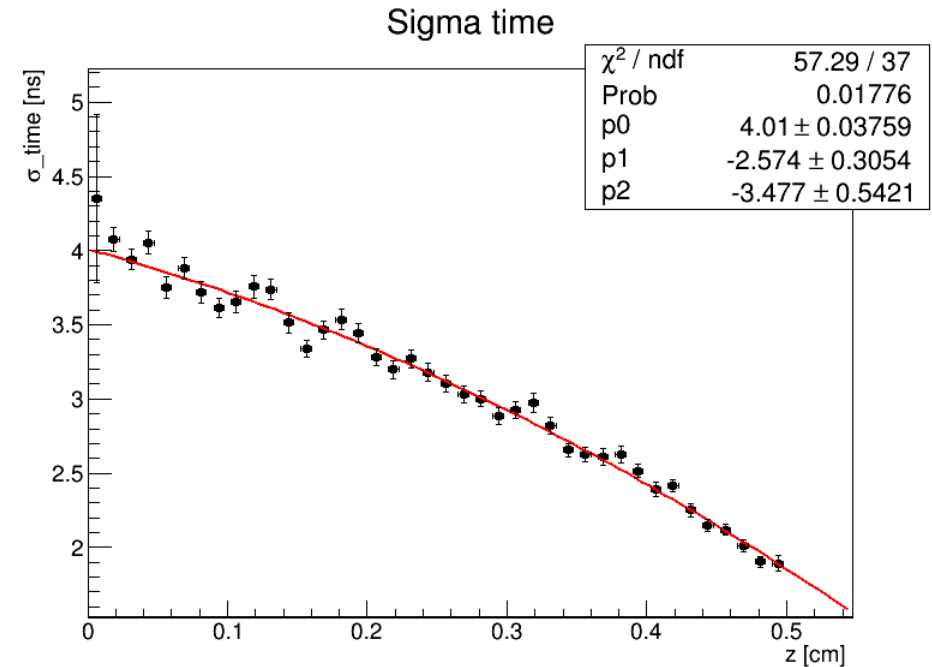
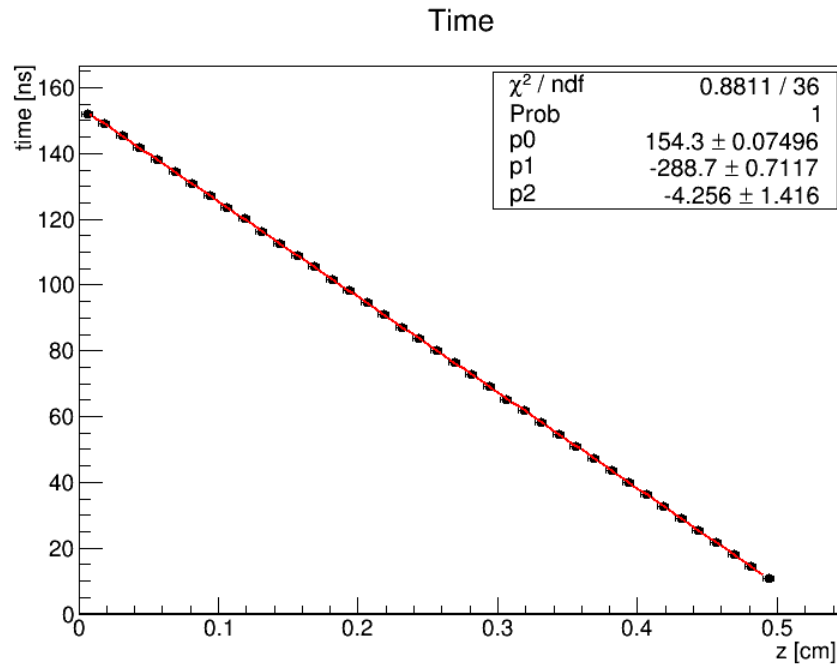


# x position

250 run

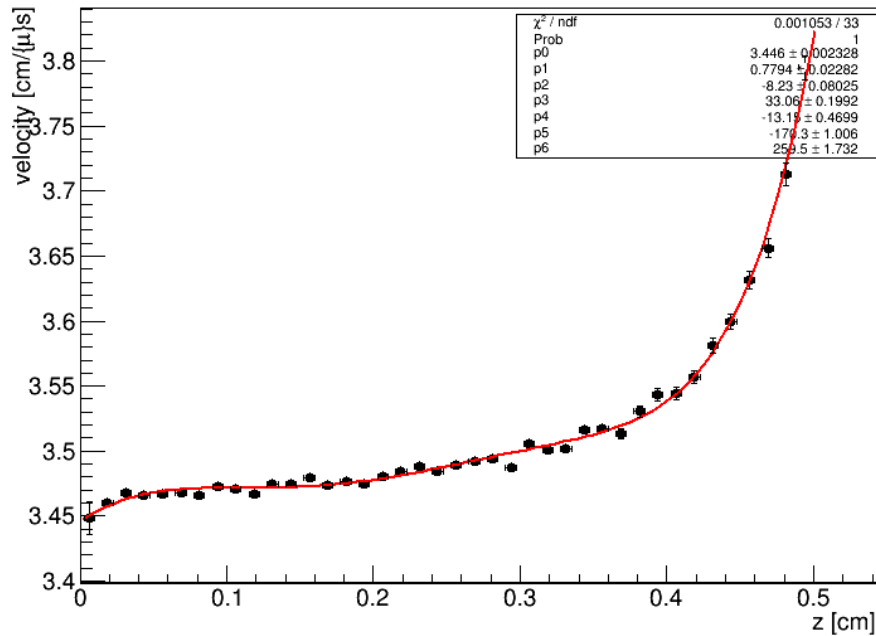


# time of arrival on anode

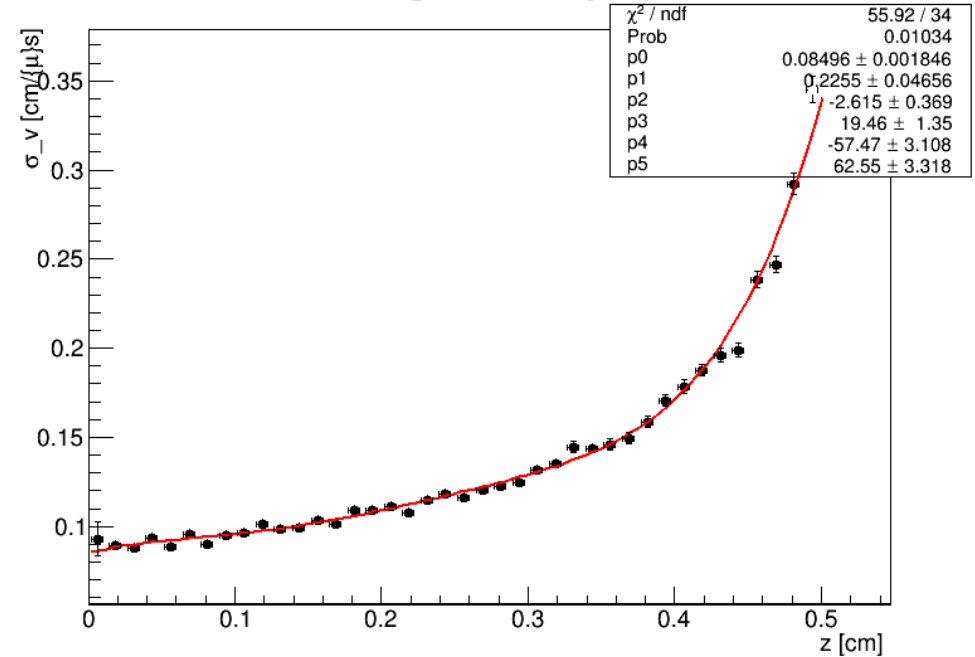


# drift velocity

Velocity



Sigma velocity



$$[\text{HERE}] V_{\text{drift}} = \frac{(x_{\text{anode}} - x_{\text{generation}})}{(t_{\text{arrival}} - t_{\text{generation}})}$$

